



# CERTIFICATE OF ACCREDITATION

**The ANSI National Accreditation Board**

Hereby attests that

**Premier Semiconductor Services LLC  
dba Micross**

**4400 140<sup>th</sup> Ave. N., Suite 140  
Clearwater, FL 33762**

Fulfills the requirements of

**ISO/IEC 17025:2017**

and the

**AS6171 Detection of Suspect/Counterfeit Parts  
Accreditation Program**

In the field of

**TESTING**

This certificate is valid only when accompanied by a current scope of accreditation document.  
The current scope of accreditation can be verified at [www.anab.org](http://www.anab.org).

Jason Stine, Vice President

Expiry Date: 06 September 2028

Certificate Number: AT-3126



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.  
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory  
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



## SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

### Premier Semiconductor Services LLC dba Micross

4400 140<sup>th</sup> Ave. N., Suite 140  
Clearwater, FL 33762

Gabriela Manugas  
Gabriela.manugas@micross.com

### TESTING

ISO/IEC 17025 Accreditation Granted: **26 June 2026**

Certificate Number: **AT-3126**

Certificate Expiry Date: **06 September 2028**

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 – Labs

Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to  
**Premier Semiconductor Services LLC dba Micross** to perform the following AS6171 slash sheet tests:

#### Mechanical Testing (Inspection and NDT)

| Specific Tests and/or Properties Measured | Specification, Standard, Method, or Test Technique                                                                                                       | Items, Materials or Product Tested                            | Key Equipment or Technology                                    |
|-------------------------------------------|----------------------------------------------------------------------------------------------------------------------------------------------------------|---------------------------------------------------------------|----------------------------------------------------------------|
| Visual Inspection                         | AS6081<br>AS6171/2<br>IDEA-STD-1010<br>Internal Procedure:<br>CLW-WI-0011<br>MIL-STD-750-2 Test Method: 2068,<br>2071<br>MIL-STD-883-2 Test Method: 2009 | Electrical, Electronic and Electromechanical (EEE) Components | Multiple Digital Microscopes and Digital Camera, Digital Scale |

## Mechanical Testing (Inspection and NDT)

| Specific Tests and/or Properties Measured                          | Specification, Standard, Method, or Test Technique                                                                                                                 | Items, Materials or Product Tested                            | Key Equipment or Technology                                                                     |
|--------------------------------------------------------------------|--------------------------------------------------------------------------------------------------------------------------------------------------------------------|---------------------------------------------------------------|-------------------------------------------------------------------------------------------------|
| Package Configuration<br>Physical Dimensions                       | AS6081<br>AS6171/2<br>IDEA-STD-1010<br>Internal Procedure:<br>CLW-WI-0011<br>MIL-STD-750-2 Test Method: 2066<br>MIL-STD-883-2 Test Method: 2016                    | Electrical, Electronic and Electromechanical (EEE) Components | Non-contact measurement tool and Calipers                                                       |
| Resistance to Solvents<br>(Remarking & Resurfacing)<br>Scrape Test | AS6081<br>AS6171/2<br>IDEA-STD-1010<br>Internal Procedure:<br>CLW-WI-0066<br>MIL-STD-202-215<br>MIL-STD-750-2 Test Method: 1022<br>MIL-STD-883-2 Test Method: 2015 | Electrical, Electronic and Electromechanical (EEE) Components | Multiple Microscopes, Hot Plate, X-Acto Knife, and Solvents                                     |
| Black Top Detection                                                | AS6081<br>AS6171/2<br>IDEA-STD-1010<br>Internal Procedure:<br>CLW-WI-0066                                                                                          | Electrical, Electronic and Electromechanical (EEE) Components | Multiple Microscopes, Hot Plate, X-Acto Knife, Dynasolve, and 1-Methyl 2- Pyrrolidinone (1-M-2) |
| Radiographic Examination<br>/ Inspection                           | AS6081<br>AS6171/5<br>IDEA-STD-1010<br>Internal Procedure:<br>CLW-WI-0067<br>MIL-STD-202-209<br>MIL-STD-750-2 Test Method: 2076<br>MIL-STD-883-2 Test Method: 2012 | Electrical, Electronic and Electromechanical (EEE) Components | X-Ray Machine, IQI set                                                                          |

This Scope of Accreditation, version 005, was last updated on: 26 June 2026 and is valid only when accompanied by the Certificate.

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[www.anab.org](http://www.anab.org)

### Mechanical Testing (Inspection and NDT)

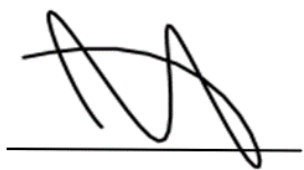
| Specific Tests and/or Properties Measured  | Specification, Standard, Method, or Test Technique                                                                                                               | Items, Materials or Product Tested                            | Key Equipment or Technology                                   |
|--------------------------------------------|------------------------------------------------------------------------------------------------------------------------------------------------------------------|---------------------------------------------------------------|---------------------------------------------------------------|
| Decapsulation and Die Verification         | AS6081<br>AS6171/4<br>IDEA-STD-1010-B<br>Internal Procedure: CLW-WI-0083<br>MIL-STD-750-2 Test Method: 2072, 2075, 2101, 2102<br>MIL-STD-883-2 Test Method: 2013 | Electrical, Electronic and Electromechanical (EEE) Components | Acid Decapsulator, Kiln, Hot Plates, Dremel, Diagonal Cutters |
| Solderability                              | Internal Procedure: CLW-WI-0068<br>IDEA-STD-1010-B<br>J-STD-002<br>MIL-STD-202-208<br>MIL-STD-750-2 Test Method: 2026<br>MIL-STD-883-2 Test Method: 2003         | Electrical, Electronic and Electromechanical (EEE) Components | Steam Ager, Bake Oven, Multiple Microscopes, and Solder Pot   |
| X-Ray Fluorescence (XRF)<br>ROHS/Thickness | AS6081<br>AS6171/3<br>IDEA-STD-1010<br>Internal Procedure: CLW-WI-0952<br>MIL-STD-750-2 Test Method: 2100<br>MIL-STD-883-2 Test Method: 2037                     | Electrical, Electronic and Electromechanical (EEE) Components | X-Ray Fluorescence (XRF) machine                              |

### Electrical

| Specific Tests and/or Properties Measured | Specification, Standard, Method, or Test Technique                     | Items, Materials or Product Tested                            | Key Equipment or Technology                                                                                     |
|-------------------------------------------|------------------------------------------------------------------------|---------------------------------------------------------------|-----------------------------------------------------------------------------------------------------------------|
| Programming/Flash/Memory                  | Internal Procedure: CLW-WI-0051                                        | Electrical, Electronic and Electromechanical (EEE) Components | Programmer                                                                                                      |
| Thermal Cycle Test (Temperature Test)     | AS6081<br>AS6171/7<br>IDEA-STD-1010<br>Internal Procedure: CLW-WI-0955 | Electrical, Electronic and Electromechanical (EEE) Components | Temperature Shock/Cycle machine, Temperature Forcing System, Bench Equipment and Automated Test Equipment (ATE) |

## Electrical

| Specific Tests and/or Properties Measured        | Specification, Standard, Method, or Test Technique                                   | Items, Materials or Product Tested                            | Key Equipment or Technology                        |
|--------------------------------------------------|--------------------------------------------------------------------------------------|---------------------------------------------------------------|----------------------------------------------------|
| DDR/SRAM                                         | Internal Procedure:<br>CLW-WI-0051                                                   | Electrical, Electronic and Electromechanical (EEE) Components | RAM Tester                                         |
| Electrical Test (Digital) Microcircuits          | MIL-STD-883-3 Class 3000<br>AS6081<br>AS6171/7<br>Internal Procedure:<br>CLW-OP-0074 | Electrical, Electronic and Electromechanical (EEE) Components | Bench Equipment and Automated Test Equipment (ATE) |
| Electrical Test (Linear) Microcircuits           | MIL-STD-883-4 Class 4000<br>AS6081<br>AS6171/7<br>Internal Procedure:<br>CLW-OP-0074 | Electrical, Electronic and Electromechanical (EEE) Components | Bench Equipment and Automated Test Equipment (ATE) |
| Transistor Electrical Test Semiconductor Devices | MIL-STD-750-3 Class 3000<br>AS6081<br>AS6171/7<br>Internal Procedure:<br>CLW-OP-0074 | Electrical, Electronic and Electromechanical (EEE) Components | Bench Equipment and Automated Test Equipment (ATE) |
| Diode Electrical test Semiconductor Devices      | MIL-STD-750-4 Class 4000<br>AS6081<br>AS6171/7<br>Internal Procedure:<br>CLW-OP-0074 | Electrical, Electronic and Electromechanical (EEE) Components | Bench Equipment and Automated Test Equipment (ATE) |



Jason Stine, Vice President